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Applicant(s)/Patent under Reexamination SHINOMIYA ET AL.

10/522,012

Art Unit

Examiner

Maria Veronica D. Ewald

1722

SEARCHED						
Class	Subclass	Date	Examiner			
425	451.6,442	6/8/2006	MVE			
425	438,398	6/8/2006	MVE			
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426	138,139	6/8/2006	MVE			
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99	383	6/9/2006	MVE			

INTERFERENCE SEARCHED							
Class	Subclass	Date	Examiner				
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SEARCH NO (INCLUDING SEARCH		)
	DATE	EXMR
Inventor search	6/9/2006	MVE
Consulted with Primary Examiner Robert Davis, AU 1722	6/9/2006	MVE
Also conducted text search in East (see search history)	6/9/2006	M∨E